

Notice of References Cited	Application/Control No. 10/617,763	Applicant(s)/Patent Under Reexamination BUM, JAE-RYONG	
	Examiner Christopher B. Shin	Art Unit 2181	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,732,222	05-2004	Garritsen et al.	711/103
*	B	US-2006/0101175	05-2006	Du et al.	710/062
*	C	US-2003/0236933	12-2003	Shigeta et al.	710/72
*	D	US-2003/0120849	06-2003	Roslak et al.	710/303
*	E	US-7,149,837	12-2006	Watts et al.	710/303
*	F	US-2003/0188144	10-2003	Du et al.	713/1
*	G	US-2004/0039876	02-2004	Nelson et al.	711/115
*	H	US-2004/0054827	03-2004	Liu et al.	710/074
*	I	US-2006/0101175	05-2006	Du et al.	710/062
*	J	US-7,054,963	05-2006	Betts-LaCroix et al.	710/62
*	K	US-6,934,794	08-2005	Garritsen et al.	711/103
*	L	US-2003/0233509	12-2003	Chang, D.C.	710/316
*	M	US-2006/0288386	12-2006	Vitito, Christopher J.	725/077

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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